



# Standard Guide to Charge Control and Charge Referencing Techniques in X-Ray Photoelectron Spectroscopy<sup>1</sup>

This standard is issued under the fixed designation E 1523; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon ( $\epsilon$ ) indicates an editorial change since the last revision or reapproval.

## 1. Scope

1.1 This guide acquaints the XPS user with the various charge control and charge shift referencing techniques that are and have been used in the acquisition and interpretation of X-ray photoelectron spectroscopy (XPS) data from surfaces of insulating specimens.

1.2 This guide is intended to apply to charge control and charge referencing techniques in XPS and is not necessarily applicable to electron-excited systems.

1.3 SI units are standard unless otherwise noted.

1.4 *This standard does not purport to address all of the safety problems, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety and health practices and determine the applicability of regulatory limitations prior to use.*

## 2. Referenced Documents

### 2.1 ASTM Standards:

E 673 Terminology Relating to Surface Analysis<sup>2</sup>

E 902 Practice for Checking the Operating Characteristics of X-Ray Photoelectron Spectrometers<sup>2</sup>

E 1078 Guide for Specimen Handling in Auger Electron Spectroscopy, X-Ray Photoelectron Spectroscopy, and Secondary Ion Mass Spectrometry<sup>2</sup>

E 1829 Guide for Specimen Preparation and Mounting in Surface Analysis<sup>2</sup>

## 3. Terminology

### 3.1 Definitions:

3.1.1 See Terminology E 673 for definitions of terms used in X-ray photoelectron spectroscopy.

## 4. Overview of Charging Effects

4.1 For insulating specimen surfaces, the emission of photoelectrons following X-ray excitation may result in a buildup of a positive surface charge. This positive surface charge changes the surface potential thereby shifting the measured energies of the photoelectron peaks to higher binding energy.

This binding energy shift may reach a nearly steady-state value of between 2 and 5 eV for spectrometers equipped with nonmonochromatic X-ray sources. The surface potential charge and the resulting binding energy shift is, generally, larger for spectrometers equipped with monochromatic X-ray sources because of the, generally, lower flux of low-energy electrons impinging on the specimen surface. This lower flux arises because focused, monochromatic X-ray beams irradiate only a portion of the specimen and not other nearby surfaces (for example, the specimen holder) that are sources of low-energy electrons. The absence of an X-ray window in many monochromatic X-ray sources (or a greater distance of the specimen from the X-ray window) also eliminates another source of low-energy electrons.

4.2 The amount of induced surface charge, its distribution across the specimen surface, and its dependence on experimental conditions are determined by several factors including specimen composition, homogeneity, magnitude of surface conductivity, total photoionization cross-section, surface topography, and availability of neutralizing electrons. The presence of particles on or different phases in the specimen surface may result in an uneven distribution of charge across the surface, a phenomenon known as differential charging. Some specimens undergo time-dependent changes in the level of charging because of electron, X-ray, or thermal damage or because of volatilization. Such specimens may never achieve steady-state potentials.

4.3 Several techniques have been developed for the purpose of controlling charge buildup and the subsequent changes in surface potential in order to obtain meaningful and reproducible data from insulating specimens. These techniques are employed during the data acquisition and are discussed in 7.1.

4.4 Several techniques have been developed for the purpose of correcting the binding energy shifts that result from surface charging. These corrections are performed after the data has been accumulated and are discussed in 7.2.

4.5 The use of the various charge control or charge referencing techniques described in this guide may depend on the available instrument as well as the specimen being analyzed.

## 5. Significance and Use

5.1 The acquisition of chemical information from variations in the energy position of peaks in the XPS spectrum is of primary interest in the use of XPS as a surface analytical tool.

<sup>1</sup> This guide is under the jurisdiction of ASTM Committee E-42 on Surface Analysis and is the direct responsibility of Subcommittee E42.03 on Auger Electron Spectroscopy and X-ray Photoelectron Spectroscopy.

Current edition approved Sept. 10, 1997. Published July 1998. Originally published as E 1523 – 93. Last previous edition E 1523 – 93.

<sup>2</sup> *Annual Book of ASTM Standards*, Vol 03.06.

Surface charging acts to shift spectral peaks independent of their chemical relationship to other elements on the same surface. The desire to eliminate the influence of surface charging on the peak positions and peak shapes has resulted in the development of several empirical methods designed to assist in the interpretation of the XPS peak positions, determine surface chemistry, and allow comparison of spectra of conducting and nonconducting systems of the same element. It is assumed that the spectrometer is generally working properly for non-insulating specimens (see Practice E 902).

5.2 No ideal method has been developed to deal with surface charging. For insulators, an appropriate choice of any control or referencing system will depend on the nature of the specimen, the instruments, and the information needed. The appropriate use of charge control and referencing techniques will result in more consistent, reproducible data. Researchers are strongly urged to report both the control and referencing techniques that have been used, the specific peaks and binding energies used as standards (if any), and the criteria applied in determining optimum results so that the appropriate comparisons may be made.

## 6. Apparatus

6.1 One or more of the charge compensation techniques mentioned in this guide may be employed in virtually any XPS spectrometer.

6.2 Some of the techniques outlined require special accessory apparatus, such as electron flood sources or a source for evaporative deposition.

6.3 Certain specimen mounting procedures, such as mounting the specimen under a fine metal mesh (1)<sup>3</sup>, can enhance electrical contact of the specimen with the specimen holder, or reduce the amount of surface charge buildup. This and other methods of specimen mounting to reduce static charge are described in detail in Guide E 1078 and Guide E 1829.

## 7. Procedures

7.1 The methods described here involve charge control (the effort to control the buildup of charge at a surface or to minimize its effect), charge referencing (the effort to determine a reliable binding energy despite buildup of charge), or some combination of the two. For charge control, peak shape is the most important parameter to consider. Correcting the peak position is accomplished separately using an appropriate charge referencing technique. In some circumstances the Auger parameter can provide chemical information without the need to resort to surface potential corrections.

### 7.1.1 *Methods to Control Surface Potential:*

7.1.1.1 *Electron Flood Gun (2-5)*—Use low-energy electron flood guns to stabilize the static charging of insulators examined by XPS (3), in particular when monochromatized X-rays are employed. Optimum operating conditions, for example, filament position, electron energy, and electron current, depend upon the orientation of the electron flood gun with respect to the specimen and upon the particular design of the electron

flood gun and must, in general, be determined by the user. Use low-electron energies (usually 10 eV or less) to maximize the neutralization effect and reduce the number of electron bombardment-induced reactions. A metal screen placed on or above the specimen can help (6,7).

7.1.1.2 *Ultraviolet Flood Lamp (8)*—Ultraviolet radiation can also produce low-energy electrons (for example, from the specimen holder) that may be useful in neutralizing specimen charging.

7.1.1.3 *Specimen Heating*—For a limited number of specimens, heating can increase the electrical conductivity of the specimen, thus decreasing charging.

7.1.1.4 *Specimen Biasing*—Applying a low-voltage bias (−10 to +10 V) to the specimen and observing the changes in the binding energies of various peaks can be used to learn about the electrical contact of a specimen (or parts of a specimen) with the specimen holder. Peaks in XPS spectrum that shift when the bias is applied are from conducting regions of the specimen. Other peaks from insulating regions may not shift nearly as much or at all and can be interpreted accordingly. This method can sometimes verify that the peaks being used for charge referencing (for example, Au 4f or C 1s) are behaving in the same manner as the peaks of interest from the specimen (1,8,9). For nonuniform or composite (nonconducting) specimens, a variety of charge shifts may be observed upon biasing.

7.1.1.5 *Low Energy Ion Source*—Recent work indicates that portions of an insulator surface can be negatively charged, even when some areas exposed to X-rays are charged positively (10). Such effects appear to be particularly important for focused X-ray beam systems, where the X-rays strike only a relatively small portion of the specimen. In these circumstances the use of a low-energy positive-ion source, in addition to an electron source, may help stabilize (and make more uniform) the surface potential of the specimen.

### 7.2 *Binding Energy Reference Methods:*

7.2.1 *Adventitious Carbon Referencing (1,2,8,11-15)*—Unless specimens are prepared for analysis under carefully controlled atmospheres, the surface, generally, is coated by adventitious contaminants. Once introduced into the spectrometer, further specimen contamination can occur by the adsorption of residual gases, especially in instruments with oil diffusion pumps. These contamination layers can be used for referencing purposes if it is assumed that they truly reflect the steady-state static charge exhibited by the specimen surface and that they contain an element with a peak of known binding energy. Carbon is most commonly detected in adventitious layers, and photoelectrons from the C 1s transition are those most often adopted as a reference.

7.2.1.1 A binding energy of 284.8 eV is often used for the C 1s level of this contamination and the difference between the measured position in the energy spectrum and the reference value, above, is the amount of surface potential shift caused by charging.

7.2.1.2 The main disadvantage of this method lies in the uncertainty of the reference values as reported in the literature (2,12,13) that ranges from 284.6 to 285.2 eV for the C 1s electrons. Therefore, it is recommended that if adventitious

<sup>3</sup> The boldface numbers given in parentheses refer to a list of references at the end of the text.